PROCEEDINGS OF SPIE

Vertical-Cavity Surface-Emitting Lasers XXIX

Kent D. Choquette Luke A. Graham Editors

29–30 January 2025 San Francisco, California, United States

Sponsored and Published by SPIE

Volume 13384

Proceedings of SPIE 0277-786X, V. 13384

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Please use the following format to cite material from these proceedings: Author(s), "Title of Paper," in Vertical-Cavity Surface-Emitting Lasers XXIX, edited by Kent D. Choquette, Luke A. Graham, Proc. of SPIE 13384, Seven-digit Article CID Number (DD/MM/YYYY); (DOI URL).

ISSN: 0277-786X ISSN: 1996-756X (electronic)

ISBN: 9781510685161 ISBN: 9781510685178 (electronic)

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